TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7MH257FK

#### Quad 2-Channel Multiplexer (3-State)

The TC7MH257FK is an advanced high speed CMOS multiplexer fabricated with silicon gate  $C^2$ MOS technology.

It achieves the high speed operation similar to equivalent bipolar schottky TTL while maintaining the CMOS low power dissipation.

It is composed of four independent 2-channel multiplexers with common SELECT and  $\overline{OUTPUTENABLE}$  ( $\overline{OE}$ ).

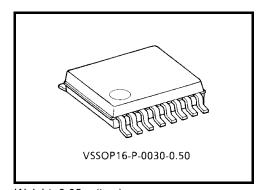
If  $\overline{OE}$  is set low, the outputs are held in a high-impedance state. When SELECT is set low, "A" data inputs are enabled.

Conversely, when SELECT is high, "B" data inputs are enabled.

An input protection circuit ensures that 0 to 5.5 V can be applied to the input pins without regard to the supply voltage.

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This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction



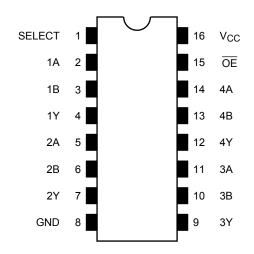
Weight: 0.02 g (typ.)

supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

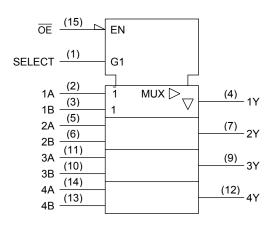
#### **Features**

- High speed:  $t_{pd} = 3.6 \text{ ns (typ.)} (V_{CC} = 5 \text{ V})$
- Low power dissipation:  $I_{CC} = 4 \mu A \text{ (max) (Ta} = 25 ^{\circ}\text{C)}$
- High noise immunity: V<sub>NIH</sub> = V<sub>NIL</sub> = 28% V<sub>CC</sub> (min)
- Power down protection is provided on all inputs.
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range:  $V_{CC (opr)} = 2 \sim 5.5 \text{ V}$
- Low noise:  $V_{OLP} = 0.8 \text{ V (max)}$
- Pin and function compatible with 74ALS257

## Pin Assignment (top view)



## **IEC Logic Symbol**



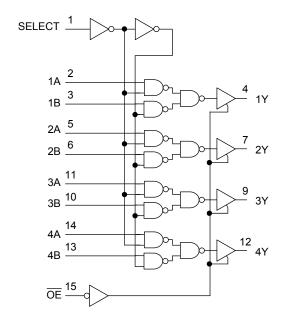
## **Truth Table**

	Outputs			
ŌĒ	Select	Α	В	Outputs
Н	Х	Х	Х	Z
L	L	L	Х	L
L	L	Н	Х	Н
L	Н	Х	L	L
L	Н	Х	Н	Н

X: Don't care

Z: High impedance

## **System Diagram**



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#### **Absolute Maximum Ratings (Note)**

Characteristics	Symbol	Rating	Unit	
Supply voltage range	$V_{CC}$	-0.5~7.0	V	
DC input voltage	V <sub>IN</sub>	-0.5~7.0	V	
DC output voltage	V <sub>OUT</sub>	-0.5~V <sub>CC</sub> + 0.5	V	
Input diode current	I <sub>IK</sub>	-20	mA	
Output diode current	I <sub>OK</sub>	±20	mA	
DC output current	lout	±25	mA	
DC V <sub>CC</sub> /ground current	Icc	±50	mA	
Power dissipation	P <sub>D</sub>	180	mW	
Storage temperature	T <sub>stg</sub>	-65~150	°C	

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit	
Supply voltage	V <sub>CC</sub>	2.0~5.5	V	
Input voltage	V <sub>IN</sub>	0~5.5	<b>V</b>	
Output voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	>	
Operating temperature	T <sub>opr</sub>	-40~85	°C	
Input rise and fall time	dt/dv	$0\sim100 \ (V_{CC}=3.3\pm0.3 \ V)$	ns/V	
input noe and fail time	avav	0~20 (V <sub>CC</sub> = 5 ± 0.5 V)	115/V	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.



## **Electrical Characteristics**

## **DC Characteristics**

Characteristics		Symbol Test Condition		Condition	on —		Ta = 25°C			Ta = -40~85°C	
		Symbol	rest Condition		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit
					2.0	1.50	_	_	1.50	_	
High level		V <sub>IH</sub>	_		3.0~5.5	V <sub>CC</sub> × 0.7	_		V <sub>CC</sub> × 0.7	_	V
Input voltage					2.0	_	_	0.50	_	0.50	V
Low level		$V_{IL}$	_		3.0~5.5	_	_	V <sub>CC</sub> × 0.3	_	V <sub>CC</sub> × 0.3	
				$I_{OH} = -50 \mu A$	2.0	1.9	2.0		1.9	_	V
		Vон	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>		3.0	2.9	3.0		2.9	_	
Output voltage	High level				4.5	4.4	4.5		4.4	_	
				$I_{OH} = -4 \text{ mA}$	3.0	2.58	_		2.48	_	
				$I_{OH} = -8 \text{ mA}$	4.5	3.94		_	3.80	_	
Output voltage		V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 50 μA	2.0	_	0	0.1	—	0.1	
	Low level				3.0	_	0	0.1	—	0.1	
					4.5	_	0	0.1	—	0.1	
				$I_{OL} = 4 \text{ mA}$	3.0	_		0.36	—	0.44	
			$I_{OL} = 8 \text{ mA}$	4.5	_	—	0.36	_	0.44		
3-state output off-state current		l <sub>OZ</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND		5.5	_	_	±0.25	_	±2.50	μА
Input leakage cu	Input leakage current $I_{IN}$ $V_{IN} = 5.5 \text{ V or GND}$		0~5.5	_	_	±0.1	_	±1.0	μΑ		
Quiescent supply current		Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	4.0	_	40.0	μΑ



## AC Characteristics (Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition			Ta = 25°C			Ta = -40~85°C		Unit
Characteristics	Symbol	rest Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Min	Max	Offic
_	t <sub>pLH</sub>		3.3 ± 0.3	15		5.8	9.3	1.0	11.0	ns
Propagation delay time				50		8.3	12.8	1.0	14.5	
(A, B-Y)	t <sub>pHL</sub>	_	5.0 ± 0.5	15		3.6	5.9	1.0	7.0	113
			3.0 ± 0.5	50		5.1	7.9	1.0	9.0	
			3.3 ± 0.3	<u> </u>	1.0	13.0				
Propagation delay time	<sup>t</sup> pLH <sup>t</sup> pHL		3.3 ± 0.3	50		9.5	14.5	1.0	16.5	ns
(SELECT-Y)		_	5.0 ± 0.5	15		4.0	6.8	1.0	8.0	
				50		5.5	8.8	1.0	10.0	
	t <sub>pZL</sub> t <sub>pZH</sub>	$R_L = 1 \text{ k}\Omega$	3.3 ± 0.3	15		6.7	10.5	1.0	12.5	- ns
3-state output enable time				50		9.2	14.0	1.0	16.0	
3-State output enable time			5.0 ± 0.5	15	_	3.6	6.8	1.0	8.0	
			5.0 ± 0.5	50	_	5.1	8.8	1.0	10.0	
3-state output disable time	t <sub>pLZ</sub>	$R_L = 1 \text{ k}\Omega$	$3.3 \pm 0.3$	50		8.6	12.0	1.0	13.5	ns
3-state output disable time	t <sub>pHZ</sub>		$5.0 \pm 0.5$	50		5.7	7.9	1.0	9.0	115
Input capacitance	C <sub>IN</sub>	-	_		_	4	10	_	10	pF
Output capacitance	C <sub>OUT</sub>	-	_			6			_	pF
Power dissipation capacitance	C <sub>PD</sub>			(Note)		23	_	_	_	pF

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

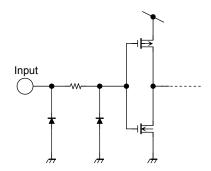
Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4 \text{ (per bit)}$ 

## Noise Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition		Ta = 25°C		- Unit
Characteristics	Syllibol	Test Condition	V <sub>CC</sub> (V)	Тур.	Limit	Offic
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	C <sub>L</sub> = 50 pF	5.0	0.3	0.8	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	C <sub>L</sub> = 50 pF	5.0	-0.3	-0.8	V
Minimum high level dynamic input voltage $V_{\mbox{\scriptsize IH}}$	V <sub>IHD</sub>	C <sub>L</sub> = 50 pF	5.0	_	3.5	V
Maximum low level dynamic input voltage $V_{\text{IL}}$	V <sub>ILD</sub>	C <sub>L</sub> = 50 pF	5.0	_	1.5	V

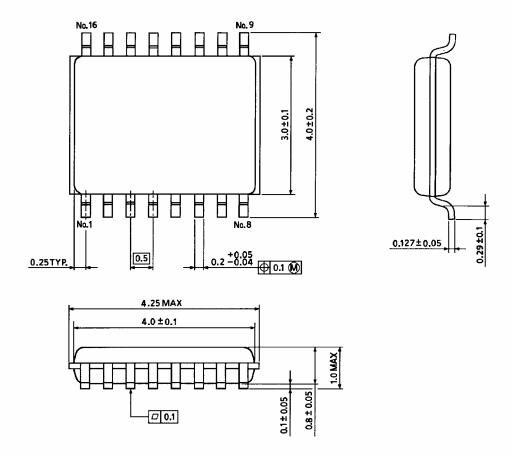
## **Input Equivalent Circuit**



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## **Package Dimensions**

VSSOP16-P-0030-0.50 Unit: mm



Weight: 0.02 g (typ.)

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20070701-EN GENERAL

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